

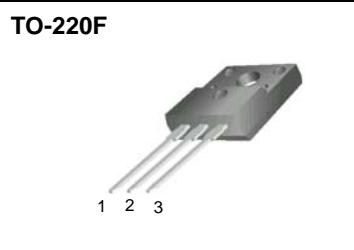
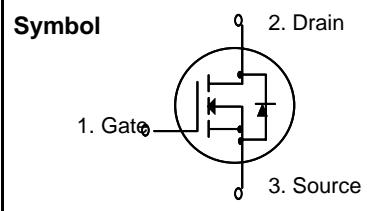


FMF10N65 10Amps 650 Voltage N Channel MOSFET

N-Channel MOSFET

Features

- $R_{DS(on)}$ (Typical 0.70 Ω) @ $V_{GS}=10V$
- Gate Charge (Typical 45nC)
- Improved dv/dt Capability, High Ruggedness
- 100% Avalanche Tested
- Maximum Junction Temperature Range (150°C)



Absolute Maximum Ratings (* Drain current limited by junction temperature)

Symbol	Parameter	Value	Units
V_{DSS}	Drain to Source Voltage	650	V
I_D	Continuous Drain Current(@ $T_C = 25^\circ C$)	10*	A
	Continuous Drain Current(@ $T_C = 100^\circ C$)	6*	A
I_{DM}	Drain Current Pulsed (Note 1)	40*	A
V_{GS}	Gate to Source Voltage	± 30	V
E_{AS}	Single Pulsed Avalanche Energy (Note 2)	812	mJ
E_{AR}	Repetitive Avalanche Energy (Note 1)	15.6	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)	4.5	V/ns
P_D	Total Power Dissipation(@ $T_C = 25^\circ C$)	50	W
	Derating Factor above 25 °C	0.4	W/°C
T_{STG}, T_J	Operating Junction Temperature & Storage Temperature	- 55 ~ 150	°C
T_L	Maximum Lead Temperature for soldering purpose, 1/8 from Case for 5 seconds.	300	°C

Thermal Characteristics

Symbol	Parameter	Value			Units
		Min.	Typ.	Max.	
R_{0JC}	Thermal Resistance, Junction-to-Case	-	-	2.5	°C/W
R_{0JA}	Thermal Resistance, Junction-to-Ambient	-	-	62.5	°C/W



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Electrical Characteristics ($T_C = 25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
Off Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_D = 250\mu\text{A}$	650	-	-	V
$\Delta BV_{DSS}/\Delta T_J$	Breakdown Voltage Temperature coefficient	$I_D = 250\mu\text{A}$, referenced to 25°C	-	0.7	-	$^\circ\text{C}$
I_{DSS}	Drain-Source Leakage Current	$V_{DS} = 650\text{V}, V_{GS} = 0\text{V}$	-	-	10	μA
		$V_{DS} = 520\text{V}, T_C = 125^\circ\text{C}$	-	-	100	μA
I_{GSS}	Gate-Source Leakage, Forward	$V_{GS} = 30\text{V}, V_{DS} = 0\text{V}$	-	-	100	nA
	Gate-source Leakage, Reverse	$V_{GS} = -30\text{V}, V_{DS} = 0\text{V}$	-	-	-100	nA
On Characteristics						
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	2.0	-	4.0	V
$R_{DS(\text{ON})}$	Static Drain-Source On-state Resistance	$V_{GS} = 10\text{V}, I_D = 5.0\text{A}$	-	0.70	0.85	Ω
Dynamic Characteristics						
C_{iss}	Input Capacitance	$V_{GS} = 0\text{V}, V_{DS} = 25\text{V}, f = 1\text{MHz}$	-	1600	-	pF
C_{oss}	Output Capacitance		-	170	-	
C_{rss}	Reverse Transfer Capacitance		-	20	-	
Dynamic Characteristics						
$t_{d(on)}$	Turn-on Delay Time	$V_{DD} = 325\text{V}, I_D = 10.0\text{A}, R_G = 4.7\Omega$ (Note 4, 5)	-	30	-	ns
t_r	Rise Time		-	70	-	
$t_{d(off)}$	Turn-off Delay Time		-	150	-	
t_f	Fall Time		-	80	-	
Q_g	Total Gate Charge	$V_{DS} = 520\text{V}, V_{GS} = 10\text{V}, I_D = 10.0\text{A}$ (Note 4, 5)	-	45	-	nC
Q_{gs}	Gate-Source Charge		-	7	-	
Q_{gd}	Gate-Drain Charge(Miller Charge)		-	20	-	

Source-Drain Diode Ratings and Characteristics

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit.
I_S	Continuous Source Current	Integral Reverse p-n Junction Diode in the MOSFET	-	-	10	A
I_{SM}	Pulsed Source Current		-	-	40	
V_{SD}	Diode Forward Voltage	$I_S = 10\text{A}, V_{GS} = 0\text{V}$	-	-	1.4	V
t_{rr}	Reverse Recovery Time	$I_S = 10\text{A}, V_{GS} = 0\text{V}, dI_F/dt = 100\text{A/us}$	-	450	-	ns
Q_{rr}	Reverse Recovery Charge		-	4.5	-	μC

* NOTES

1. Repetitivity rating : pulse width limited by junction temperature
2. $L = 15.0\text{mH}, I_{AS} = 10.0\text{A}, V_{DD} = 50\text{V}, R_G = 25\Omega$, Starting $T_J = 25^\circ\text{C}$
3. $I_{SD} \leq 10.0\text{A}, di/dt \leq 200\text{A/us}, V_{DD} \leq BV_{DSS}$, Starting $T_J = 25^\circ\text{C}$
4. Pulse Test : Pulse Width $\leq 300\text{us}$, Duty Cycle $\leq 2\%$
5. Essentially independent of operating temperature.



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Typical Characteristics

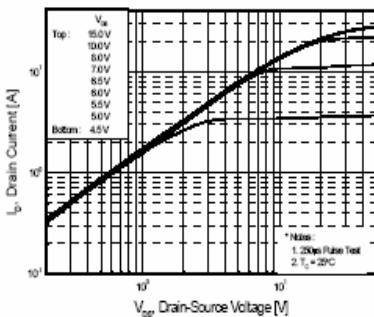


Figure 1. On-Region Characteristics

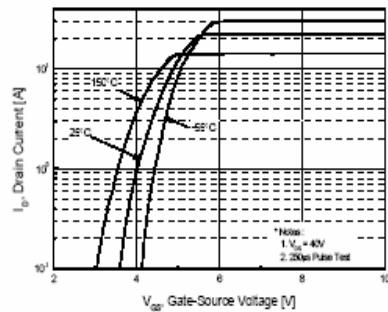


Figure 2. Transfer Characteristics

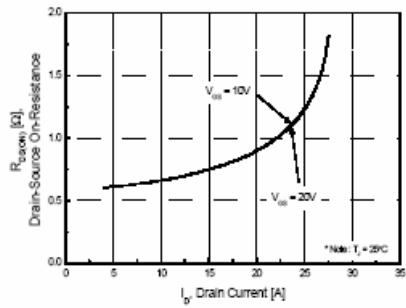


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

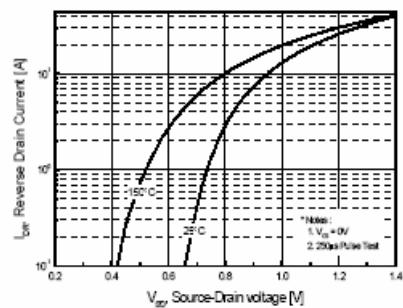


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

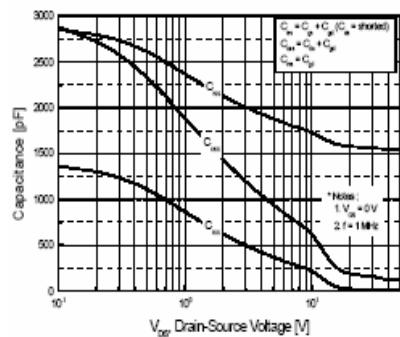


Figure 5. Capacitance Characteristics

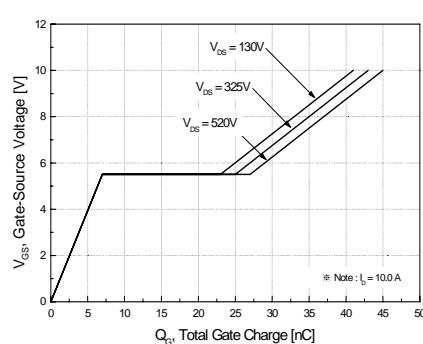


Figure 6. Gate Charge Characteristics



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Typical Characteristics (Continued)

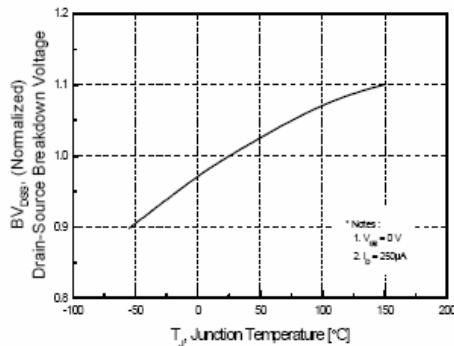


Figure 7. Breakdown Voltage Variation vs Temperature

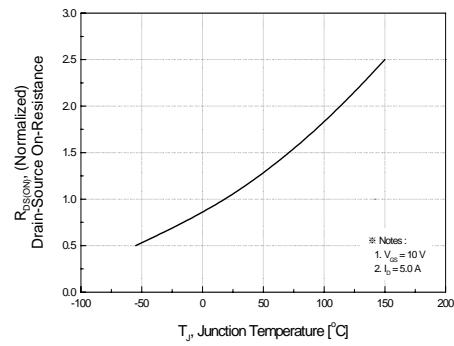


Figure 8. On-Resistance Variation vs Temperature

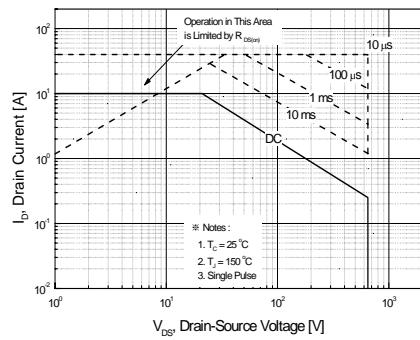


Figure 9. Maximum Safe Operating Area

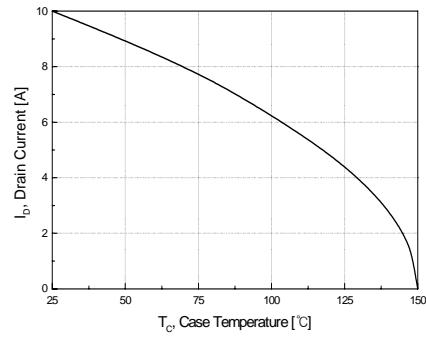


Figure 10. Maximum Drain Current vs Case Temperature

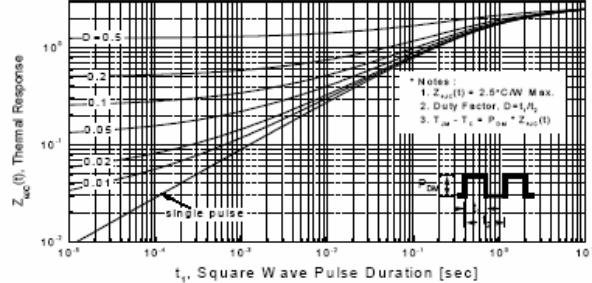
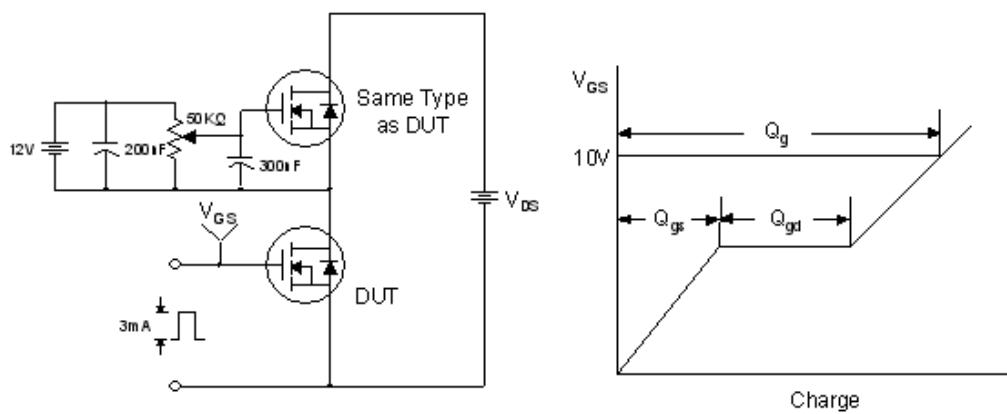


Figure 11. Transient Thermal Response Curve

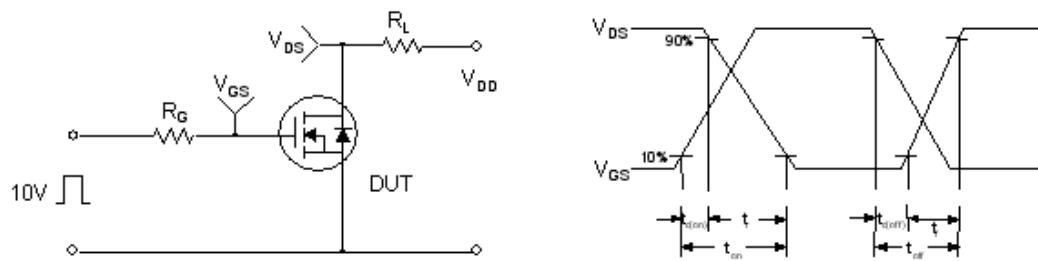


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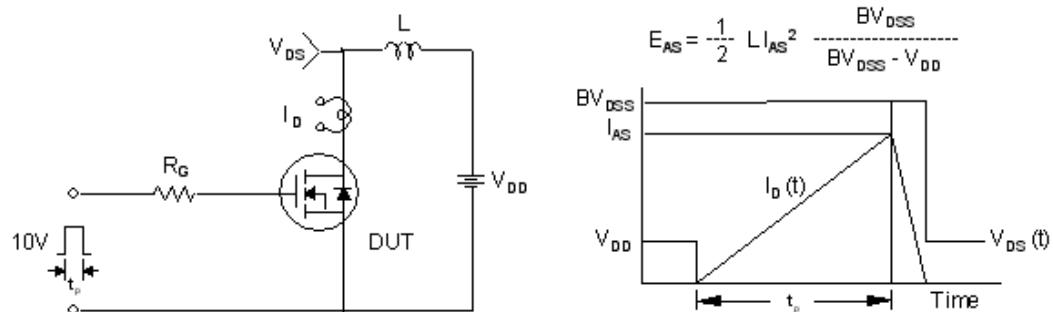
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms



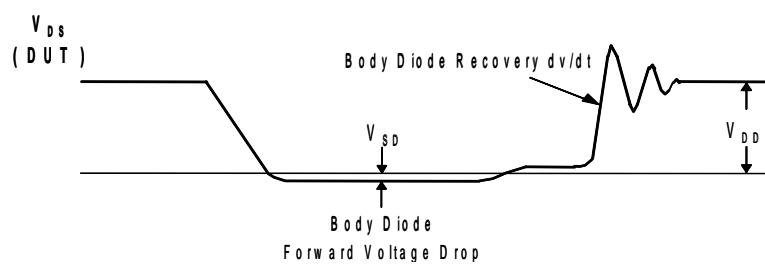
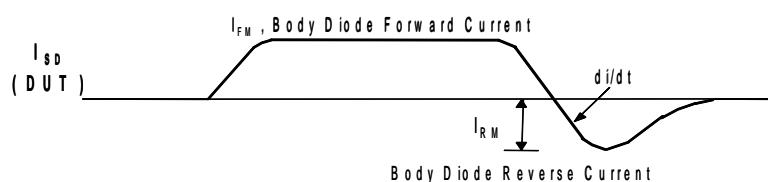
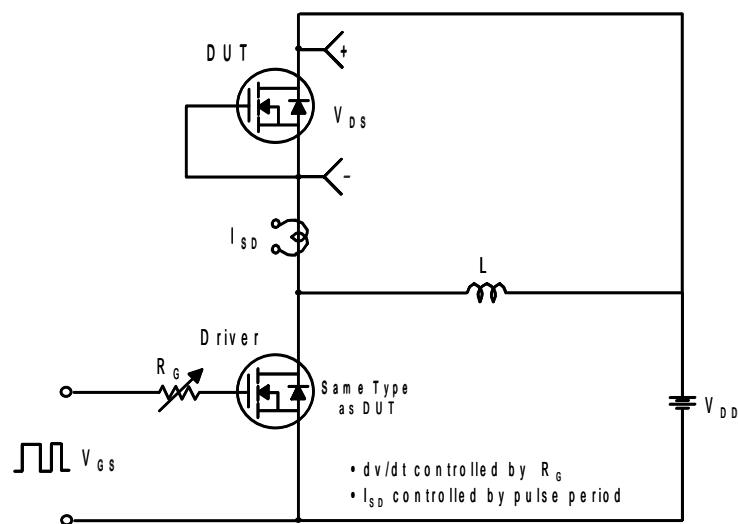
Unclamped Inductive Switching Test Circuit & Waveforms





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Peak Diode Recovery dv/dt Test Circuit & Waveforms





FMF10N65 10Amps 650 Voltage N Channel MOSFET

Package Dimensions

ITO-220

